

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G8 SMD CRYSTAL
SPEC. NO. (P/N)	G83270021
CUSTOMER P/N	
ISSUE DATE	Jun.16,2016
VERSION	Α

APPROVED	PREPARED	QA
Brenda	Clame	Dong Jang
APPROVED BY	APPROVED BY CUSTOMER:	
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PSE Technology Corporation

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E0-R-4-014 Rev. E Page i

G83270021

VER. A

1-Jun-16

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
01	Jun.1,2016			New	
02	Jun.2,2016			Updated Temperature Coefficient & C0 Added Reliability	
03	Jun.15,2016			Updated Shunt Capacitance & Motional Capacitance	
А	Jun.16,2016			Release formal version	

G83270021

VER. A 1-Jun-16

ELECTRICAL SPECIFICATIONS

SRe Part Number: G83270021

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25°C ± 5°C
Load Capacitance	CL	12.5	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ. / Max.
Equivalent Series Resistance	ESR	70	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	± 0.01ppm/°C ²
Operating Temperature Range	TR	-40 to 85	°C	
Shunt Capacitance	C0	1.5	pF	Тур.
Motional Capacitance	C1	6.5	fF	Тур.
Quality Factor	Q	13	K	Min.
Aging		± 3	ppm	Max. 1st year
Storage Temperature Range		-40 to 85	°C	
Insulation Resistance		500	МΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm
2	Shear test	Apply 20N(2.04kgf) static load to the core of quartz crystal units in the direction of the arrow using a R0.5 scratch tool, then hold for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ
	Core body strength	Apply 10N(1.02kgf) static load to the quartz crystal units center in the direction of the arrow using a R0.5 pushing tool, then hold for 10 seconds.	
4	Vibration	Frequency sweep method shall be applied as follows. Quartz crystal units shall be vibrated with the sweeping frequency from 10Hz to 55Hz and return to 10Hz in 1 minute, with 1.5mm amplitude. This vibration shall be applied for 2 hours in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-6.	
5	Shock	Quartz crystal units shall be accelerated at 9810m/s2 by 1ms pulse duration. This shock shall be applied 3 times in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-27.	

G83270021

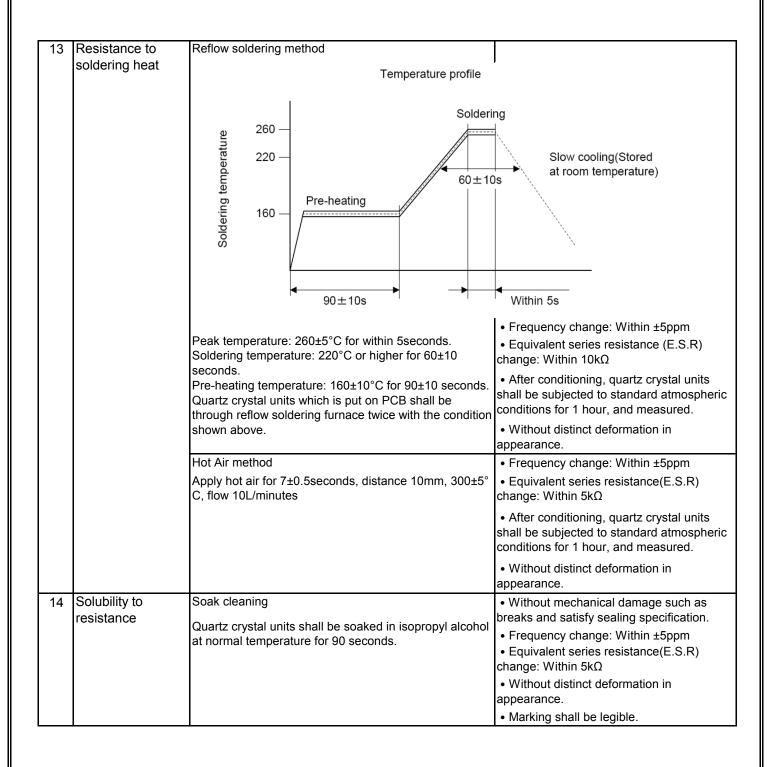
VER. A 1-Jun-16

6	Cold		/stal units shall re for 1000 hou 0068-2-1.		 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ 	
7	Dry heat	Quartz crystal units shall be stored in the 100±2℃ atmosphere for 100 hours. Other procedures conform to				After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat	Quartz crystal units shall be stored in the 40±2°C atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3.				
9	Change of temperature	cycles of t	vstal units shall emperature chass conform to JI			
			Temperat	ture	Duration	
		1	-40±3°C		30min.	
		2	Normal tempe	rature	Within 30 sec.	
		3	100±2℃		30min.	
		4	Normal tempe	rature	Within 30 sec.	
10	Sealing	Both the test methods specified below shall be applied.				
		Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes.				Without repetitive leaking bubbles from quartz crystal units.
		spectrome	uartz crystal units shall be tested by Mass ectrometric leakage detector to measure the leakage te of helium gas.			• 1×10-9 Pa·m3/s or less
11	Aging	Quartz crystal units shall be stored in the 85±3°C atmosphere for 720±12 hours.			 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ 	
					 After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. 	
12	Solder-ability Terminals coated with flux shall be immersed in the solder bath for 3.5±0.5 seconds.				pe immersed in the	Minimum 95% of immersed terminal shall be covered with new uniform solder.
			Items		Conditions	
		1	Solder	Sn-3	.0Ag-0.5Cu	
		2	Flux	meth	roximately 25wt% nanol(JIS K 8891) tion of resin(JIS K 2).	
			Solder			



G83270021

VER. A 1-Jun-16

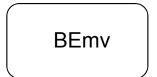


G83270021

VER. A

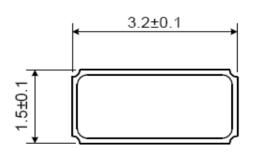
1-Jun-16

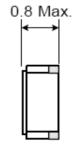
Marking

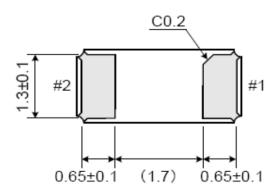




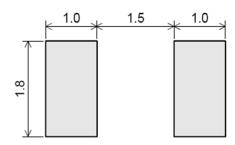
Dimensions (Units: mm)



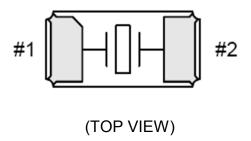




Recommended Soldering Pattern



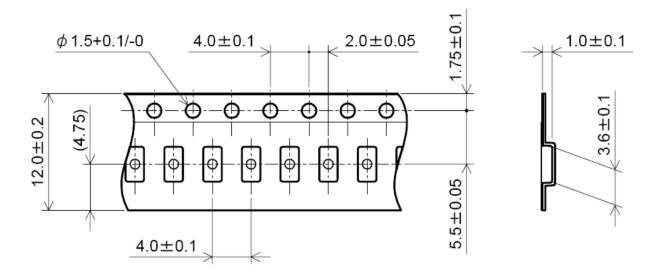
Internal connection



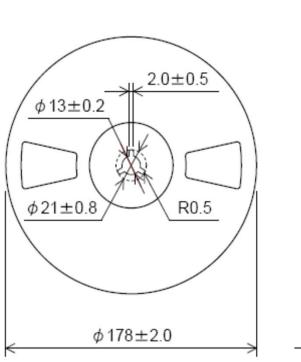
G83270021

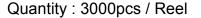
VER. A 1-Jun-16

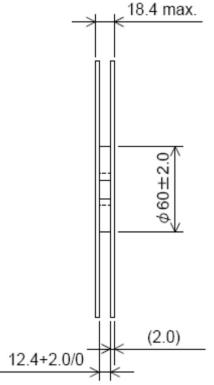
TAPING (Units: mm)



REEL (Units: mm)







E0-R-4-014 Rev. E Page 5